# EMC TESTING CENTER OF THE COMPANY «INTERSTANDARD»

# A CERTIFICATE OF ACCREDITATION OF THE TESTING LABORATORY № POCC RU.0001.21M954



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# Electromagnetic Compatibility

**Test of: Telecom Analyzer** 

**Model Number: Bercut-ETX** 

Applicant: JSC NTC "Metrotek"

Test Type: Compliance

Test Specification: EN 55022:2006, EN 55024:1998+A1:2001+A2:2003,

EN 61000-3-2:2006, EN 61000-3-3:1995+A1:2001+A2:2005

Date of Receipt: 2011, July 12

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This report refers only to the sample submitted for test.

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Product: **Bercut-ETX** 

Rev.:1

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# 1. Client Information

Company Name: JSC NTC "Metrotek"

Address: 21/3, Yablochkova str., Moscow, Russia, 127322

Contact name: Company director: A.M.Feldman

Tel./fax: +7 495 9610071

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#### 2. **Equipment Under Test (EUT)**

#### 2.1 **Identification Of EUT**

Model Number:	Bercut-ETX	
Unique Identifier:	S/N 8001	
Description of EUT:	Bercut-ETX is intended for 10G ethernet network equipment testing	
Supply Voltage:	AC adapter-input:100-240V AC 1.2 A 50-60 Hz;	
	Output: 19V DC 2.1A	
	Internal rechargeable battery – 4.8V	
Ports present:	10G Ethernet port	
	LAN port (Ethernet 10/100)	
	USB	
	DC 15V, 230 V, 50 Hz (power adapter)	
Accessories Supplied:	AC/DC Adapter ADP-40 PH BB LPS	
	Notebook Acer	
	Ethernet patch-cord (optical)	

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# 3. Test Specification, Methods and Procedures

# 3.1 Test Specification(s)

Standard	Title
EN55022 : 2006	Information technology equipment – Radio disturbance characteristics – Limits and methods of measurement
EN 55024 : 1998 A1 : 2001	Information Technology Equipment - Immunity characteristics. Limits and methods of measurement
A2:2003	
EN 61000-3-2:2006	Electromagnetic compatibility
	Limits for harmonic current emissions (equipment input current ≤ 16 A per phase)
EN 61000-3-3:1995	Electromagnetic compatibility
A1:2001	Limitation of voltage fluctuations and flicker in low
A2:2005	voltage supply systems for equipment with rated of 16A or less

# 3.2 Purpose Of Test

To perform the relevant tests and assess the product for compliance with the above specification.

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# 3.3 Methods and Procedures

The standards listed on the previous page refer to the following tests: -

Basic Standard	Date	Description	
EN55022	2006	Information technology equipment – Radio disturbance characteristics – Limits and methods of measurement	
		Conducted Emissions	
		Radiated Emissions	
EN 61000-3-2	2006	Electromagnetic compatibility	
		Limits for harmonic current emissions (equipment input current ≤ 16 A per phase)	
EN 61000-3-3:	1995	Electromagnetic compatibility	
A1	2001	Limitation of voltage fluctuations and flicker in low voltage	
A2	2005	supply systems for equipment with rated of 16A or less	
EN 61000-4-2	1995	Testing and measurement techniques.	
A1	1998	Electrostatic discharge immunity test.	
A2	2001		
EN 61000-4-3	2006	Testing and measurement techniques.	
		Radiated, radio frequency, electromagnetic field immunity test	
EN 61000-4-4	2004	Testing and measurement techniques.	
		Electrical fast transient/burst immunity test.	
EN 61000-4-5	2006	Testing and measurement techniques.	
Surge immunity test.		Surge immunity test.	
EN 61000-4-6	61000-4-6 2007 Testing and measurement techniques.		
		Immunity to conducted disturbances, induced by radio frequency fields	
EN 61000-4-8	1993	Testing and measurement techniques.	
A1	2001	Power frequency magnetic field immunity test	
EN 61000-4-11	2004	Testing and measurement techniques	
		Voltage dips, short interruptions and voltage variations immunity tests	

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# 4. Deviations or Exclusions from the Test Specifications

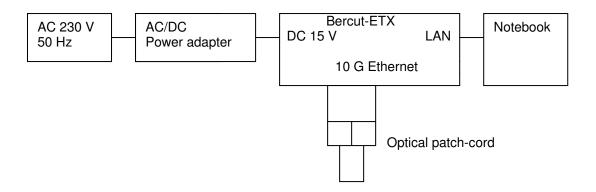
For testing, the standards refer to dated basic standards. However for some tests, testing has been performed to later amended standards. Please refer to individual test results section of this report for details of the versions of basic standards actually used for testing.

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# 5. Operation of the EUT During Testing

#### 5.1 Configuration and Peripherals



Notebook is not included in the supplied complete set. USB port is used only for programming.

#### 5.2 Operating Mode and Environmental Conditions

The operating modes and environmental conditions used for each individual test are described in the test results section of this report.

The EUT operating mode was like those used in real applications. During test procedures the EUT has performed the following functions:

- analysis of the test signal passing quality along the loop optical line via the port 10G
   Ethernet
- transference of the analysis results to the notebook via the port LAN

#### 5.3 Performance Criteria A

The apparatus shall continue to operate as intended without operator intervention during and after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

# **Performance Criteria B**

After the test the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

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#### Performance Criteria C

Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.

Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

## 5.4 Monitoring of the EUT

During the testing there were controlled telecommunication (exchange of data) availability of the notebook with EUT via the port LAN and stability of the data of analysis results via 10G Ethernet on the notebook display.

#### 5.5 EUT Specific Performance Criteria

#### **Performance Criteria A**

Telecommunication (exchange of data) with the notebook should not be interrupted; the readings of analysis results on the notebook display should be reflected continuously.

#### Performance Criteria B

During the application of the test disturbance interruption of telecommunication (exchange of data) of the EUT with the notebook is allowed; settings are kept. After the test disturbance ceased the operation automatically restored with given parameters.

#### Performance Criteria C

During the application of the test disturbance and after ceasing, telecommunication (exchange of data) with the notebook has interrupted. The EUT and the notebook restarting for restore operation was needed.

# 6. Test Results

# 6.1 General Comments

Details of the test methods used can be found in the EMC Testing Center procedures manual.

#### 6.2 Modifications Made to the EUT

No modifications were made to the EUT during the testing process.

# 6.3 Summary of Test Results

Basic Standard	Test	Result
EN 55022	Information technology equipment – Radio disturbance	Complied
	characteristics – Limits and methods of measurement	Class B
	Conducted Emissions. Mains ports	
EN 55022	Information technology equipment – Radio disturbance characteristics – Limits and methods of measurement	Complied
	Conducted Emissions. Telecommunication ports	Clfss B
EN 55022	Information technology equipment – Radio disturbance	Complied
	characteristics – Limits and methods of measurement	Class A
	Radiated Emissions.	
EN 61000-3-2	Electromagnetic compatibility	N/A
	Harmonics	Note 1
EN 61000-3-3	Electromagnetic compatibility	N/A
	Flicker	Note 2
EN 61000-4-2	Testing and measurement techniques.	Complied
	Electrostatic discharge immunity test.	Criteria B
EN 61000-4-3	Testing and measurement techniques.	Complied
	Radio Frequency immunity test.	Criteria A
EN 61000-4-4	Testing and measurement techniques.	Complied
	Electrical fast transient/burst immunity test.	Criteria A
		Note 3
EN 61000-4-5	Testing and measurement techniques.	Complied
	Surge immunity test.	Criteria B
		Note 3
EN 61000-4-6	Testing and measurement techniques.	Complied
	Conducted Immunity	Criteria A
		Note 3
EN 61000-4-8	Testing and measurement techniques.	N/A
	Magnetic Field Immunity	Note 4
EN 61000-4-11	Testing and measurement techniques.	Complied
	Voltage Dips and interruptions	Criteria A

Note 1. Not applicable, rated power less than 50 W (max 10 W)

**Note 2.** Not applicable. Tests need not be made on equipment which is unlikely to produce significant voltage fluctuations or flicker. This device is supplied from inside battery which is DC rechargeable up to 0.5 A from AC/DC power adapter. Mains supplied current without fluctuations, which could cause flicker.

**Note 3.** Testing was performed only for port A.C. power and LAN, as USB and DC power cables do not exceed the length 3 m; 10G Ethernet port is connected to the optical cable.

**Note 4.** Not applicable as the device does not contain magnetic sensitive elements.

## Result

In the configuration tested, the EUT complies with the test standards detailed above.

Full details of all tests can be found in the test results section of this report.

# 6.4 Radiated Emissions Test Results

Basic Standard	EN 55022:2006
Limit	Class A

Frequency Range: 30 MHz ÷ 6 GHz

#### **Operating Mode**

Analysis of the test signal passing quality along the loop optical line via the port 10G Ethernet. Transference of the analysis results to the notebook via the port LAN

#### **Test Results**

Horizontal Polarisation Worst Cases Emissions

#### Quasi Peak Measurements

Frequency	Quasi Peak Measurement	Quasi Peak Limit
(MHz)	(dBμV/m)	(dBμV/m)
33.18662	18.9	30.0
38.70892	21.3	30.0
40.12710	18.4	30.0
104.95916	19.6	30.0
135.02303	28.1	30.0
184.98745	28.3	30.0
295.02339	29.9	37.0
340.01295	26.4	37.0
544.97932	26.7	37.0
739.95913	29.0	37.0
863.95225	23.2	37.0
892.03156	25.3	37.0

# Vertical Polarisation Worst Cases Emissions Quasi Peak Measurements

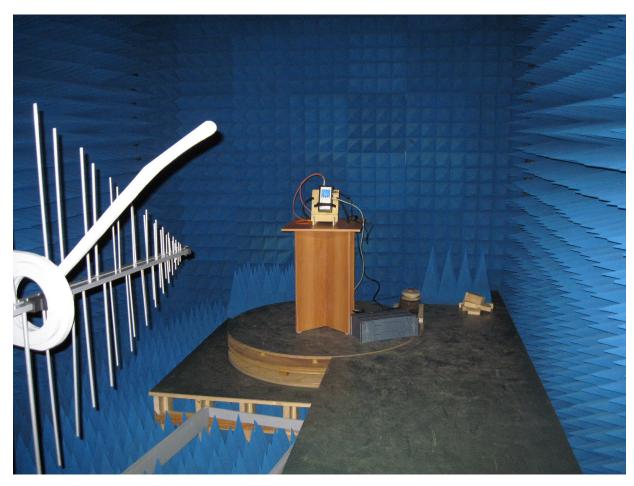
Frequency	Quasi Peak Measurement	Quasi Peak Limit	
(MHz)	(dBμV/m)	(dBμV/m)	
33.18662	35.4	40.0	
38.70892	34.1	40.0	
40.36847	31.2	40.0	
68.97755	25.9	40.0	
104.95916	22.9	40.0	
135.02303	29.9	40.0	
184.98745	31.1	40,0	
295.02339	32.9	47,0	
624.95484	22.3	47.0	
739.95913	26.0	47.0	
999.68932	25.4	47.0	

**Note.** The radiated emission measurements were performed in anechoic chamber according to p.7.2.9.2 and p.7.3 of CISPR 16-2-3:2006, the measurement distance was 3m. The correlation coefficient is included in the Test Receiver ESS and is taken into consideration automatically.

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# **Radiated Emissions Test Configuration**

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## **Radiated Emissions Environmental Conditions**

Power Supply	A.C. 230 V, 50 Hz	
Temperature	20°C	
Relative Humidity	70%	
Barometric Pressure	740mb	

## **Radiated Emissions Measurement Uncertainties**

Frequency	± 10kHz
Amplitude	± 4.6dB

The uncertainties stated are calculated in accordance with the requirements of UKAS with a confidence level of 95%.

# **Radiated Emissions Test Equipment Used**

<b>Equipment Type</b>	Model Number	Serial Number	Cal. Date	Cal. Due
Test Receiver	Rohde&Schwarz ESS	0830262/004	06.06.2011	06.06.2012
	HP8564 E	3846 AO1470	04.04.2010	04.04.2012
Antenna	EMCO 3144,	9906-1059	19.04.2010	19.04.2012
	EMKO 3109	9906-3228	19.04.2010	19.04.2012
	BBHA 9120 D	495	19.04.2010	19.04.2012

# **6.5 Conducted Emissions Test Results**

Basic Standard	EN 55022: 2006
Limit	Class B

# **Operating Mode**

Analysis of the test signal passing quality along the loop optical line via the port 10G Ethernet. Transference of the analysis results to the notebook via the port LAN

#### **Test Results**

Port: A.C. Mains ports

## Continuous disturbance Line Terminal Worst Case Emissions

Frequency (MHz)	Quasi Peak Measurement (dBμV)	Quasi Peak Limit (dBμV)
0.15363	52.1	65.8
0,18899	52.2	64.1
0.23436	43.7	62.3
0.28375	40.0	60.7
0.35467	35.5	58.9
0.55414	29.6	56.0
0.70941	25.2	56.0
1.22934	23.2	56.0
2.23466	22.8	56.0
3.49141	27.7	56.0
4.32948	26.2	56.0
5.58692	19.7	60.0
12.19846	28.1	60.0
16.77746	34.9	60.0
20.80466	39.9	60.0
30.00000	47.7	60.0

Frequency (MHz)	Average Measurement (dBµV)	Average Limit (dBμV)
0.15241	21.4	55.8
0.19983	38.9	53.6
0.26411	27.0	51.3
0.34355	23.2	49.1
0.46876	19.3	46.5
0.55414	15.4	46.0
1.24909	11.7	46.0
2.23466	12.3	46.0
3.19842	17.4	46.0
4.32948	16.7	46.0
9.45296	15.5	50.0
12.19846	23.6	50.0

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# **Neutral Terminal Worst Case Emissions**

Frequency (MHz)	Quasi Peak Measurement (dBμV)	Quasi Peak Limit (dBμV)
0.15241	50.9	65.8
0.19051	52.8	64.0
0.25994	45.2	61.4
0.28602	40.1	60.7
0.43285	32.0	57.2
0.83197	24.0	56.0
1.29986	20.7	56.0
2.93001	22.2	56.0
4.39903	24.9	56.0
5.54258	17.7	60.0
12.19846	29.3	60.0
16.77746	34.7	60.0
20.80466	40.1	60.0
30.00000	37.6	60.0

Frequency (MHz)	Average Measurement (dBµV)	Average Limit (dBμV)
0.15486	21.7	55.7
0.19668	35.6	53.8
0.25994	26.8	51.4
0.32233	18.8	49.7
0.48010	16.2	46.4
2,14738	10.0	46.0
3.19842	15.7	46.0
5.11808	17.3	50.0
7.03928	11.9	50.0
12.19846	24.6	50.0

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# **Conducted Emissions Test Configuration (AC mains)**



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Port: Telecommunication ports (LAN)

Frequency (MHz)	Quasi Peak Measurement (dBμV)	Quasi Peak Limit (dBμV)
0.20143	42.9	81.5
0.31977	44.3	77.7
0.53250	45.6	74.0
0.81231	49.4	74.0
1.23917	61.6	74.0
1.33130	65.5	74.0
1.54891	60.4	74.0
5.90740	57.9	74.0
12.19846	64.2	74.0
20.80466	64.7	74.0
24.59415	58.2	74.0

Frequency (MHz)	Average Measurement (dBµV)	Average Limit (dBμV)
0.16637	31.5	73.2
0.20143	38.4	71.5
0.31977	39.5	67.7
0.35186	40.1	66.9
0.93015	44.9	64.0
1.40767	53.2	64.0
2.36285	44.3	64.0
4.46970	47.3	64.0
5.90740	56.4	64.0
12.19846	63.0	64.0
15.61642	62.4	64.0

Product: Bercut-ETX

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# **Conducted Emissions Test Configuration (Port LAN)**



Product: **Bercut-ETX** Rev.:1

## **Conducted Emissions Environmental Conditions**

Power Supply	A.C. 230V, 50 Hz
Temperature	20°C
Relative Humidity	70%
Barometric Pressure	740 mb

## **Conducted Emissions Measurement Uncertainties**

Frequency	± 10kHz
Amplitude	± 2.9dB

The uncertainties stated are calculated in accordance with the requirements of UKAS with a confidence level of 95%.

# **Conducted Emissions Test Equipment Used**

Equipment Type	Model Number	Serial Number	Cal. Date	Cal. Due
LISN	PMM L3-32	0120F90401	16.05.2010	16.05.2012
Test receiver	Rohde&Schwarz ESS	0830262/004	06.06.2011	06.06.2012
ISN	ISN T400	16870	11.10.2010	11.10.2012

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# 6.6 Harmonics Test Results

Basic Standard	EN 61000-3-2:2006
Limit	Class A
Test Time:	10.5 minutes

Not applicable, rated power less than 10 W

# 6.7 Flicker

Basic Standard	EN 61000-3-3:1995, A1:2001, A2:2005
Limit	EN 61000-3-3, c.5, listing a)
Short time	10 min
Period	12

Not applicable. Tests need not be made on equipment which is unlikely to produce significant voltage fluctuations or flicker. This device is supplied from inside battery which is DC rechargeable up to 0.5 A from AC/DC power adapter. Mains supplied current without fluctuations, which could cause flicker.

# 6.8 Electrostatic Discharge Test Results

Basic Standard	EN 61000-4-2:1995+A1:1998+A2:2001
Limit	EN 55024: 1998 + A1:2001+ A2:2003 Table 1

Port: Enclosure (to 10 points on each side of enclosure including all

the screws, connectors, coupling planes)

**Test Level:**  $\pm 4 \text{ kV}$  contact discharge

± 8 kV air discharge.

(Contact discharge is the preferred method, and air discharge is to be used

where contact discharge is not possible).

#### **Operating Mode**

Analysis of the test signal passing quality along the loop optical line via the port 10G Ethernet. Transference of the analysis results to the notebook via the port LAN

#### **Test Results**

Test Voltage (kV)	Discharge Type	Application	Observation
± 2	Air	Enclosure	Note 1
± 4	Air	Enclosure	Note 1
± 8	Air	Enclosure	Note 2
± 2	Contact	Enclosure	Note 1
± 4	Contact	Enclosure	Note 1
± 2	Contact	VCP	Note 1
± 4	Contact	VCP	Note 1
± 2	Contact	HCP	Note 1
± 4	Contact	HCP	Note 1

Air discharge was applied only where contact discharge was not possible.

VCP = Vertical Coupling Plane

HCP = Horizontal Coupling Plane

Note 1: No degradation in performance of the EUT was observed during the test.

**Note 2:** Telecommunication (exchange of data) with the notebook during application of the test disturbance was interrupted. After the test disturbance ceased the operation was restored without the operator intervention. The settings were kept. Criteria B. It complies to EN 55024 Table 1.

For VCP and HCP tests, discharges were made on each of the four sides of the EUT. The result 'Enclosure' refers to all possible discharge points around the enclosure.

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# **Electrostatic Discharge Test Configuration**



Product: **Bercut-ETX** Rev.:1

# **Electrostatic Discharge Environmental Conditions**

Power Supply	A.C. 230 V, 50 Hz
Temperature	20°C
Relative Humidity	70%
Barometric Pressure	740mb

# **Electrostatic Discharge Measurement Uncertainties**

Current Pulse	Current Pulse 1 to 35 amps pulse width < 2ns	
	1 to 35 amps pulse width > 2ns	±5.5%
Rise Time 0.5 to 10ns		± (5%+0.05ns)
Time Interval	10 to 100ns	±3%
DC Voltage	0 to 30kV	±2 %

The uncertainties stated are calculated in accordance with the requirements of UKAS with a confidence level of 95%.

# **Electrostatic Discharge Test Equipment Used**

Equipment Type	Model Number	Serial Number	Cal. Date	Cal. Due
ESD Simulator	ESP30/P18	0999-03	29.05.2010	29.05.2012
	EM TEST			

# 6.9 Radiated Immunity Test Results

<b>Basic Standard</b> EN 61000-4-3: 2006	
Limit	EN 55024:1998+A1:2001+ A2:2003
	Table 1

Port: Enclosure Test Level: 3 V/m

Frequency Range: 80MHz – 1 GHz

**Dwell Time:** 2 second

**Modulation:** 80%, 1kHz Amplitude Modulation.

# **Operating Mode**

Analysis of the test signal passing quality along the loop optical line via the port 10G Ethernet. Transference of the analysis results to the notebook via the port LAN

#### **Test Results**

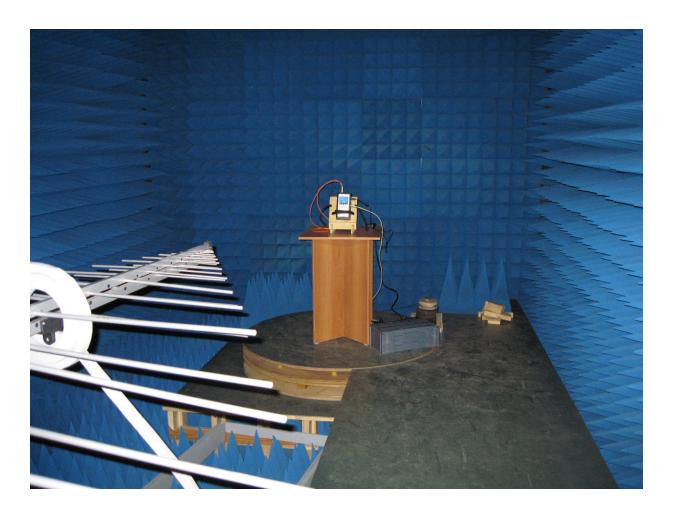
EUT Face	EUT Face Polarity	
Front	Horizontal	Note 1
Front	Vertical	Note 1
Rear	Horizontal	Note 1
Rear	Vertical	Note 1
LHS	Horizontal	Note 1
LHS	Vertical	Note 1
RHS	Horizontal	Note 1
RHS	Vertical	Note 1

**Note 1:** No degradation in performance of the EUT was observed during the test.

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# **Radiated Immunity Test Configuration**

Product: Bercut-ETX



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# **Radiated Immunity Environmental Conditions**

Power Supply	A.C. 230 V, 50 Hz
Temperature	20°C
Relative Humidity	70%
Barometric Pressure	740mb

# **Radiated Immunity Measurement Uncertainties**

Frequency	± 10kHz	
Field Level	± 4.0dB	
(Field Probe Uncertainty)		

The uncertainties stated are calculated in accordance with the requirements of UKAS with a confidence level of 95%.

# **Radiated Immunity Test Equipment Used**

Equipment Type	Model Number	Serial Number	Cal. Date	Cal. Due
Antenna	EMCO 3144	9906-1059	19.04.2010	19.04.2012
Amplifier	Kalmus LA1000VUFG	•	25.04.2010	25.04.2012
Signal Generator	Aeroflex IFR 2032	203003/007	25.04.2010	25.04.2012

#### 6.10 **Fast Transients/Burst Test Results**

Basic Standard	EN 61000-4-4:2004	
Limit	EN 55024:1998+A1:2001+ A2:2003 Table 2, Table 4	

Port: A.C. Mains port, port LAN

Note. Testing was performed only for port A.C. power and LAN, as USB and DC power cables do not exceed the length 3 m; 10G Ethernet port is connected to the optical cable.

## **Operating Mode**

Analysis of the test signal passing quality along the loop optical line via the port 10G Ethernet. Transference of the analysis results to the notebook via the port LAN

#### **Test Results**

A.C. Mains port

Line	Test Voltage (kV)	Coupling (Direct / Clamp)	Observations
Line+Neutral	±0,5	Direct	Note 1
	±1		

The test duration was 1 minute, with a 30-second recovery time, repetition rate 5 kHz.

Note 1: No degradation in performance of the EUT was observed during the test.

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# Fast Transients/Burst Test Configuration (AC mains)



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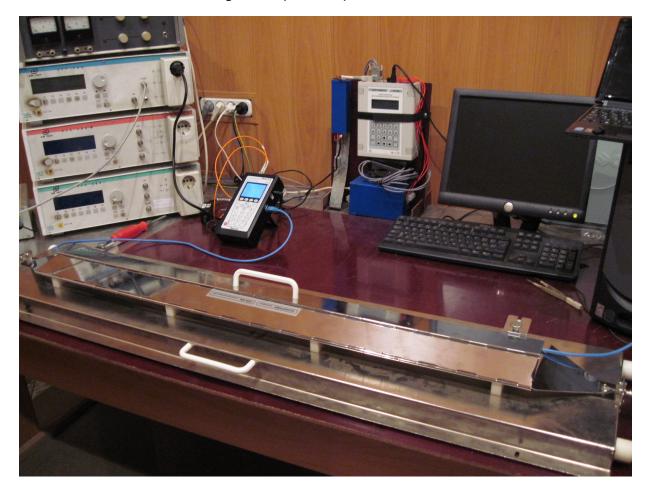
# Port LAN

Line	Test Voltage (kV)	Coupling (Direct / Clamp)	Observations
LAN (Ethernet)	± 0,25 ± 0,5	Clamp	Note 1

The test duration was 1 minute, with a 30-second recovery time, repetition rate 5 kHz.

Note 1: No degradation in performance of the EUT was observed during the test.

# Fast Transients/Burst Test Configuration (Port LAN)



Product: **Bercut-ETX** Rev.:1

## **Fast Transients/Burst Environmental Conditions**

Power Supply	A.C.230V,50 Hz
Temperature	20°C
Relative Humidity	70 %
Barometric Pressure	740 mb

#### **Fast Transients / Burst Measurement Uncertainties**

The instruments specified are subject to periodic calibration. Monthly controls ensure, with 95% confidence level, that the instruments remain within the calibrated levels.

# **Fast Burst Transients Test Equipment Used**

Equipment Type	Model Number	Serial Number	Cal. Date	Cal. Due
Disturbance	EFT 500	1198-07	04.06.2010	04.06.2012
simulator	EM TEST			

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# 6.11 Surge Test Results

Basic Standard	EN 61000-4-5:2006
Limit	EN 55024:1998+A1:2001+ A2:2003
	Table 2, Table 4

Port: A.C. Mains port, port LAN

**Note.** Testing was performed only for port A.C. power and LAN, as USB and DC power cables do not exceed the length 3 m; 10G Ethernet port is connected to the optical cable.

## **Operating Mode**

Analysis of the test signal passing quality along the loop optical line via the port 10G Ethernet. Transference of the analysis results to the notebook via the port LAN

# **Test Results** A.C. Mains port

Pulse Application	Test Voltage	Observations
	kV	
Line – Earth	+0.5	Note
	-0,5	Note
	+1	Note
	-1	Note
	+2	Note
	-2	Note
Neutral – Earth	+0.5	Note
	-0,5	Note
	+1	Note
	-1	Note
	+2	Note
	-2	Note
Line - Neutral	+0.5	Note
	-0,5	Note
	+1	Note
	-1	Note

Note: No degradation in performance of the EUT was observed during the test.

Rev.:1

# **Surge Test Configuration (AC mains)**

Product: Bercut-ETX



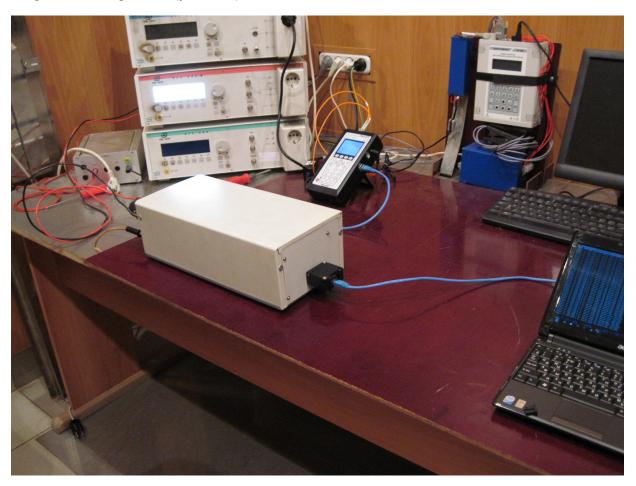
#### Port LAN

Line	Test Voltage (kV)	Observations
Port LAN (Ethernet)	+ 0, 5	Note 1
	- 0,5	Note 1
	+ 1	Note 2
	- 1	Note 2

Note 1: No degradation in performance of the EUT was observed during the test.

**Note 2**. Telecommunication (exchange of data) with the notebook during application of the test disturbance—was interrupted. After the test disturbance ceased the operation was restored without the operator intervention. The settings were kept. Criteria B. It complies to EN 55024 Table 2.

# **Surge Test Configuration (port LAN)**



Product: **Bercut-ETX** Rev.:1

# **Surge Environmental Conditions**

Power Supply	A.C.230V,50 Hz
Temperature	20°C
Relative Humidity	70%
Barometric Pressure	740 mb

# **Surge Measurement Uncertainties**

The instruments specified are subject to periodic calibration. Monthly controls ensure, with 95% confidence level, that the instruments remain within the calibrated levels.

# **Surge Test Equipment Used**

Equipment Type	Model Number	Serial Number	Cal. Date	Cal. Due
Disturbance simulator	VCS 500 M EM TEST	0498-08	05.06.2010	05.06.2012

"INTERSTANDARD" Product: Bercut-ETX Rev.:1

# 6.12 Voltage Dips Test Results

Basic Standard	EN 61000-4-11: 2004
Limit	EN 55024:1998+A1:2001+ A2:2003
	Table 4

Port: A.C. Mains port

## **Operating Mode**

Analysis of the test signal passing quality along the loop optical line via the port 10G Ethernet. Transference of the analysis results to the notebook via the port LAN

## **Test Results**

Residual voltage %	Duration (periods)	Performance Criterion	Observation
0	0,5	В	Note 1
70	25	С	Note 1
0	250	С	Note 1

Note 1. No degradation in performance of the EUT was observed during the test.

## **Voltage Dips Environmental Conditions**

Power Supply	A.C. 230V, 50 Hz	
Temperature	20°C	
Relative Humidity	70%	
Barometric Pressure	740 mb	

# **Voltage Dips Measurement Uncertainties**

The instruments specified are subject to periodic calibration. Monthly controls ensure, with 95% confidence level, that the instruments remain within the calibrated levels.

## **Voltage Dips Test Equipment Used**

Equipment Type	Model Number	Serial Number	Cal. Date	Cal. Due
Disturbance	PFS 500	0499-01	04.06.2010	04.06.2012
simulator	EM TEST			

Rev.:1

# **Voltage Dips Test Configuration**



"INTERSTANDARD"

Product: **Bercut-ETX** Rev.:1

# 6.13 Conducted Immunity Test Results

Basic Standard	IEC 61000-4-6: 2007
Limit	EN 55024:1998+A1:2001+ A2:2003 Table 2, Table 4

Port: A.C. Mains ports, port LAN

**Note.** Testing was performed only for port A.C. power and LAN, as USB and DC power cables do not exceed the length 3 m; 10G Ethernet port is connected to the optical cable.

Test level 3V

Frequency Range: 0.15 to 80MHz
Dwell Time: 2 second
Frequency Step Size: 1%

Modulation: 80%, 1kHz Amplitude Modulation

## **Operating Mode**

Analysis of the test signal passing quality along the loop optical line via the port 10G Ethernet. Transference of the analysis results to the notebook via the port LAN

#### **Test Results**

A.C. Mains port

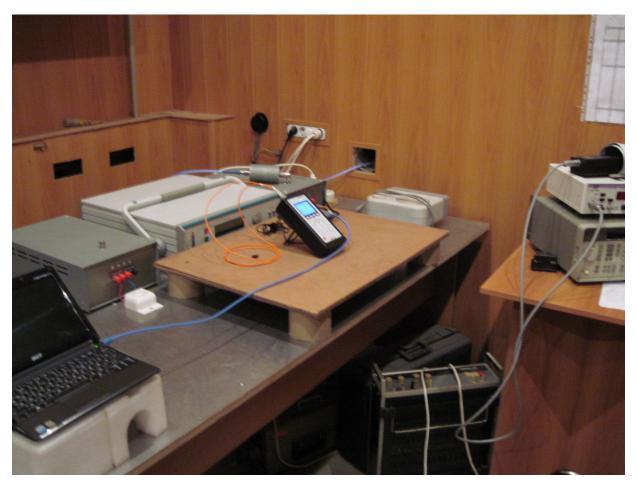
Test Voltage (Vrms)	Frequency Range (MHz)	Observations	
3	0.15 – 80	Note 1	

Note 1: No degradation in the performance of the EUT was observed during the test.

Product: Bercut-ETX

Rev.:1

# **Conducted Immunity Test Configuration (AC mains)**



Port LAN

Test Voltage (Vrms)	Frequency Range (MHz)	Observations	
3	0.15 – 80	Note 1	

Note 1: No degradation in the performance of the EUT was observed during the test.

# **Conducted Immunity Test Configuration (Port LAN)**



"INTERSTANDARD"
Product: **Bercut-ETX**Rev.:1

# **Conducted Immunity Environmental Conditions**

Power Supply	A.C.230V, 50 Hz	
Temperature	20°C	
Relative Humidity	70%	
Barometric Pressure	740 mb	

# **Conducted Immunity Measurement Uncertainties**

The instruments specified are subject to periodic calibration. Monthly controls ensure, with 95% confidence level, that the instruments remain within the calibrated levels.

# **Conducted Immunity Test Equipment Used**

Equipment Type	Model Number	Serial Number	Cal. Date	Cal. Due
Amplifier	Kalmus 137C	-	10.06.2010	10.06.2012
Coupling / Decoupling Network	USR 2/4	-	10.06.2010	10.06.2012
Signal Generator	HP 8648 B	3P47U02340	10.06.2010	10.06.2012

"INTERSTANDARD"

Product: **Bercut-ETX** Rev.:1

ANNEX 1 The photo of the product, configuration and peripherals





Product: Bercut-ETX

Rev.:1

